

Product Overview

Qorvo's TGA2214 is a wideband power amplifier fabricated on Qorvo's QGaN15 GaN on SiC process. The TGA2214 operates from 2–18 GHz and achieves 5 W of saturated output power with 14 dB of large signal gain and greater than 20 % power-added efficiency.

This combination of wideband power, gain and efficiency provides system designers the flexibility to improve system performance while reducing size and cost.

The TGA2214 is matched to 50 Ω with integrated DC blocking capacitors on both RF ports simplifying system integration; it is ideally suited for electronic warfare, test instrumentation and radar applications across both military and commercial markets.

Lead free and RoHS compliant.

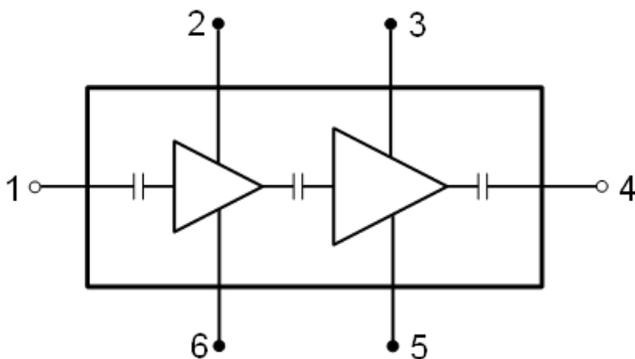


Key Features

- Frequency Range: 2 – 18 GHz
- P_{OUT}: 37 dBm @ P_{IN} = 23 dBm
- PAE: 20 % @ P_{IN} = 23 dBm
- Large Signal Gain (P_{IN} = 23 dBm): 14 dB
- Small Signal Gain: 22 dB
- Return Loss: 7 dB
- Bias: V_D = +22 V, I_{DQ} = 450 mA, V_G = -2.3 V Typical
- Chip Dimensions: 2.87 x 4.87 x 0.10 mm
- Performance under CW operation

Performance is typical across frequency. Please reference electrical specification table and data plots for more details.

Functional Block Diagram



Applications

- Test Equipment
- Electronic Warfare
- Military Radar

Ordering Information

Part No.	Description
TGA2214	2 – 18 GHz 5W GaN Power Amplifier
TGA2214EVB01	TGA2214 Evaluation Board

Absolute Maximum Ratings

Parameter	Rating
Drain Voltage (V_D)	+29.5 V
Gate Voltage Range (V_G)	-5 to 0 V
Drain Current, 1 st Stage (I_{D1})	0.5 A
Drain Current, 2 nd Stage (I_{D2})	1.0 A
Gate Current (I_G)	See plot, page 10
Power Dissipation (P_{DISS}), 85 °C	30 W
Input Power (P_{IN}), CW, 50 Ω , 85 °C	31 dBm
Input Power (P_{IN}), CW, VSWR 3:1, 85 °C	31 dBm
Mounting Temperature (30 s)	320 °C
Storage Temperature	-55 to +150 °C

Exceeding any one or a combination of the Absolute Maximum Rating conditions may cause permanent damage to the device. Extended application of Absolute Maximum Rating conditions to the device may reduce device reliability.

Recommended Operating Conditions

Parameter	Value / Units
Drain Voltage (V_D)	+22 V
Drain Current (I_{DQ})	450 mA
Operating Temperature (T_{BASE})	-40 to 85 °C

Electrical specifications are measured at specified test conditions. Specifications are not guaranteed over all recommended operating conditions.

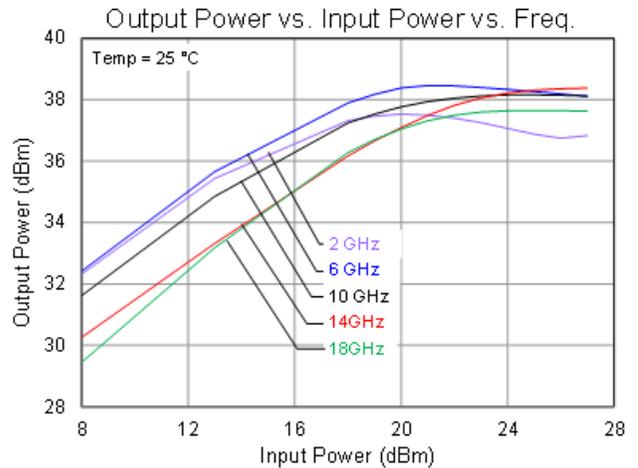
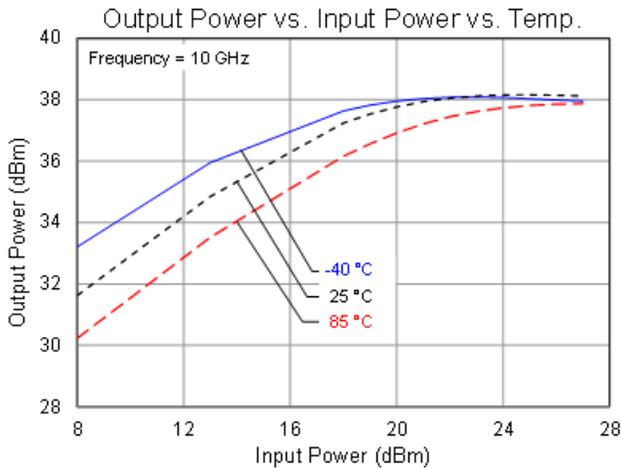
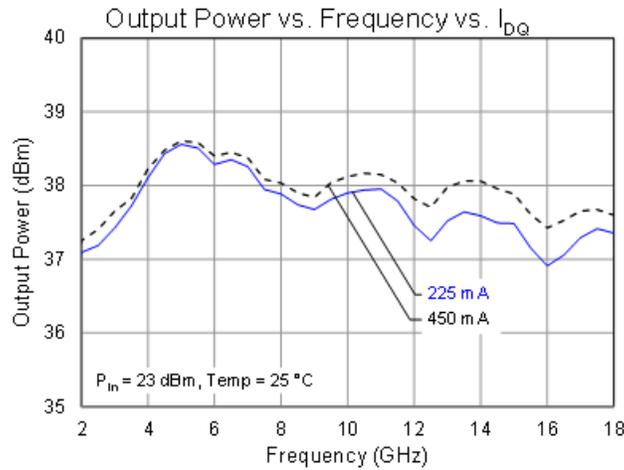
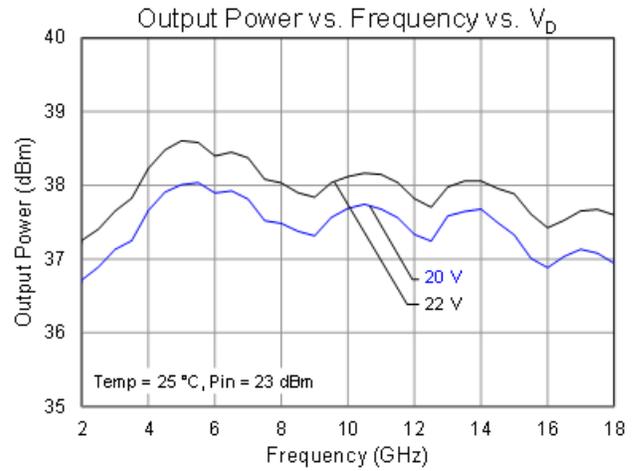
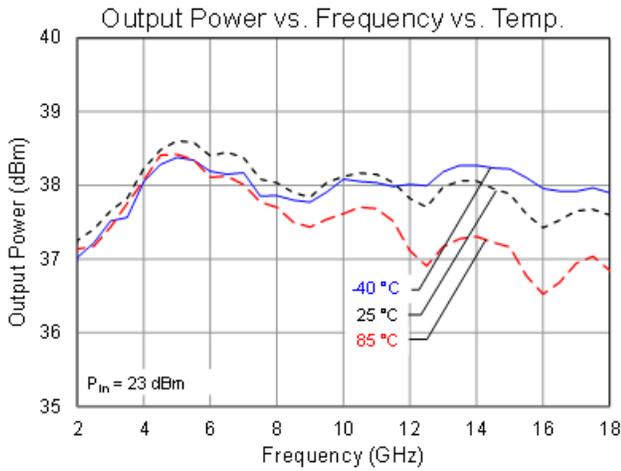
Electrical Specifications

Parameter		Min	Typ	Max	Units
Operational Frequency Range		2		18	GHz
Output Power ($P_{IN} = 23$ dBm)	Frequency = 2 GHz	36	37.3	–	dBm
	Frequency = 10 GHz	35	38.1	–	
	Frequency = 18 GHz	35	37.6	–	
Power Added Eff. ($P_{IN} = 23$ dBm)	Frequency = 2 GHz	17.0	22.8	–	%
	Frequency = 10 GHz	13.5	21.4	–	
	Frequency = 18 GHz	12.0	21.6	–	
Small Signal Gain	Frequency = 2 GHz	–	25.4	–	dB
	Frequency = 10 GHz	–	25	–	
	Frequency = 18 GHz	–	22	–	
Input Return Loss	Frequency = 2 GHz	–	10.2	–	dB
	Frequency = 10 GHz	–	11	–	
	Frequency = 18 GHz	–	13.5	–	
Output Return Loss	Frequency = 2 GHz	–	9	–	dB
	Frequency = 10 GHz	–	13.5	–	
	Frequency = 18 GHz	–	12.5	–	
IM3 ($P_{OUT}/Tone = 31$ dBm/Tone, 100 MHz spacing)		–	-20	–	dBc
IM5 ($P_{OUT}/Tone = 31$ dBm/Tone, 100 MHz spacing)		–	-33	–	dBc
Small Signal Gain Temperature Coefficient		–	-0.04	–	dB/°C
Output Power Temperature Coefficient		–	-0.008	–	dBm/°C

Test conditions unless otherwise noted: 25 °C, $V_D = +22$ V, $I_{DQ} = 450$ mA, CW

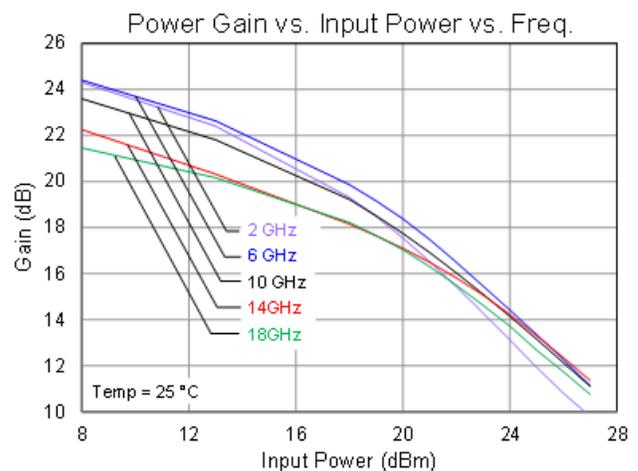
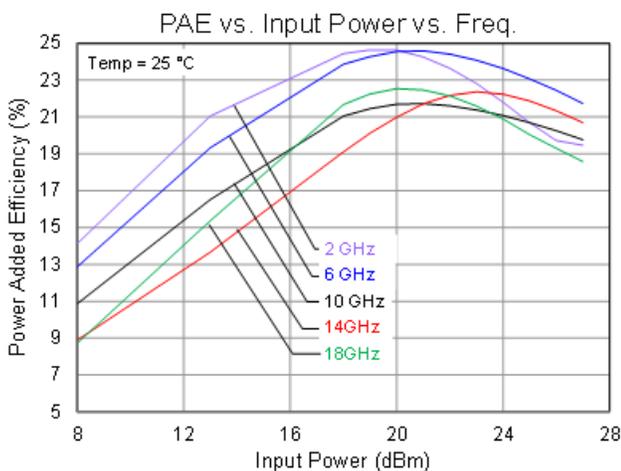
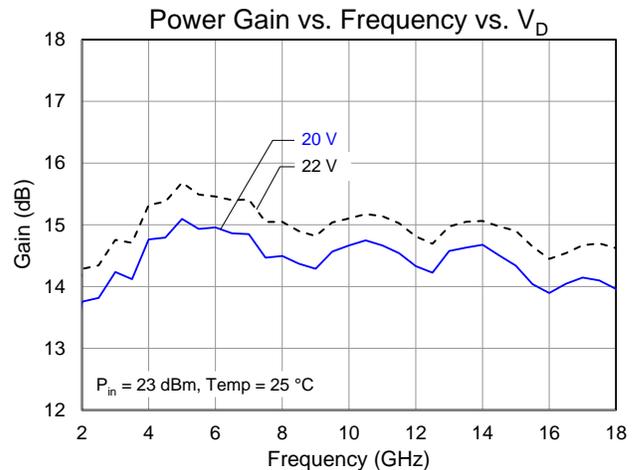
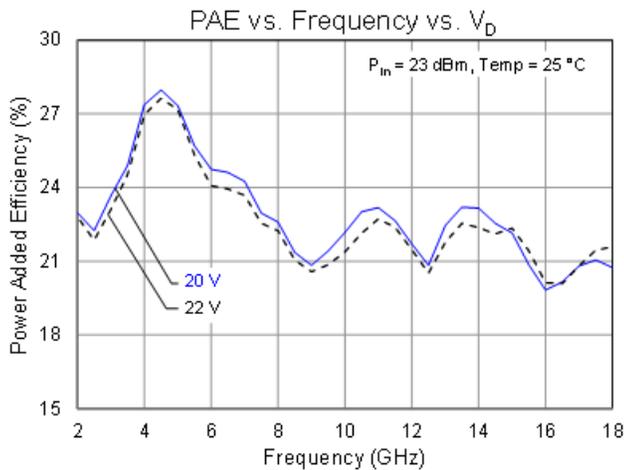
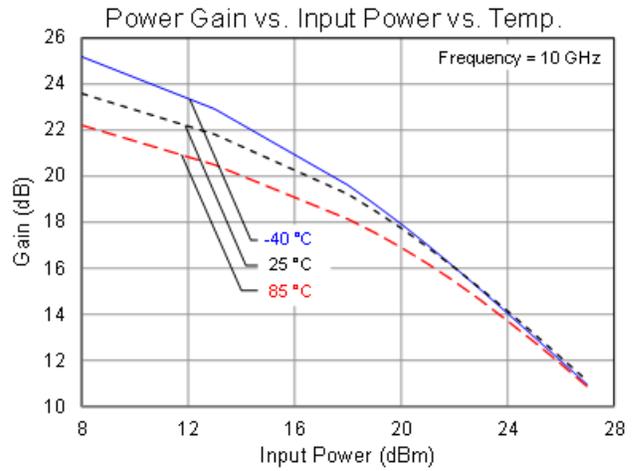
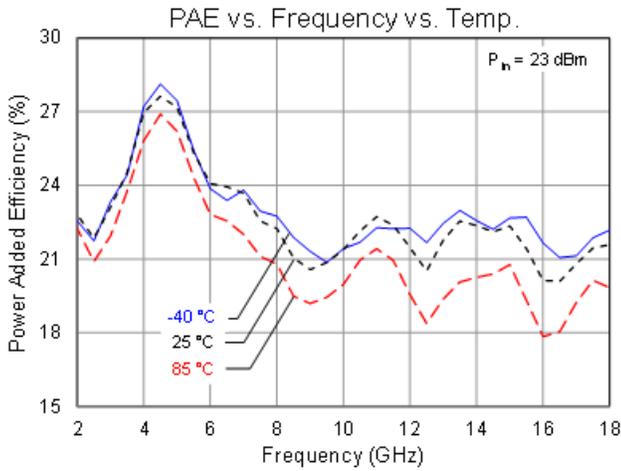
Performance Plots – Large Signal

Test conditions unless otherwise noted: 25 °C, $V_D = +22\text{ V}$, $I_{DQ} = 450\text{ mA}$, CW.



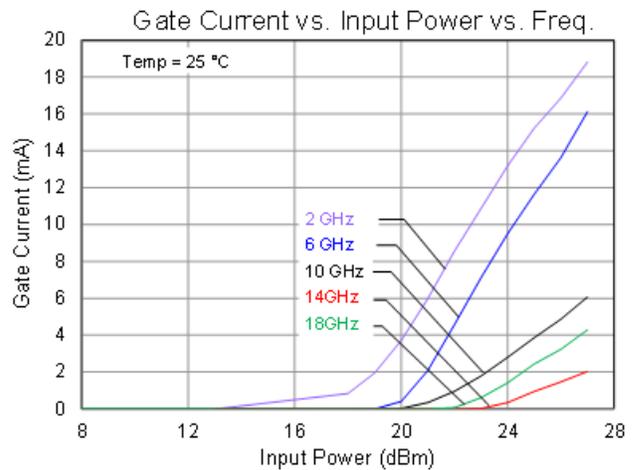
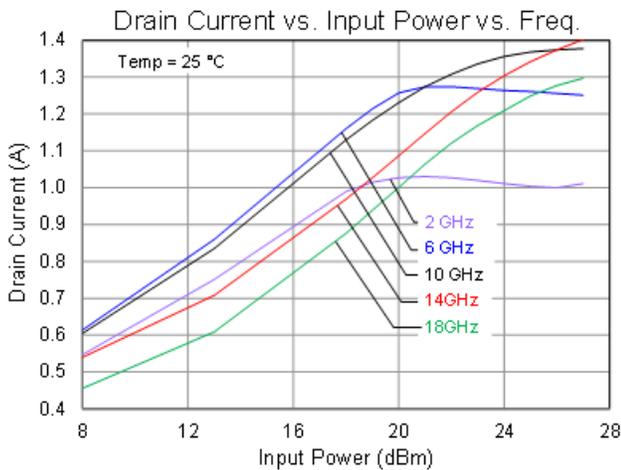
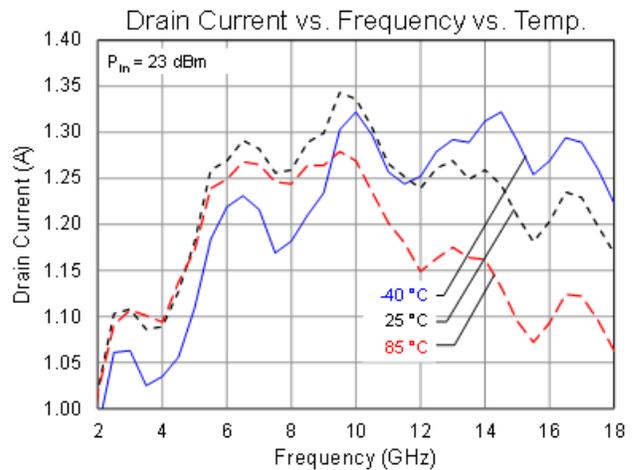
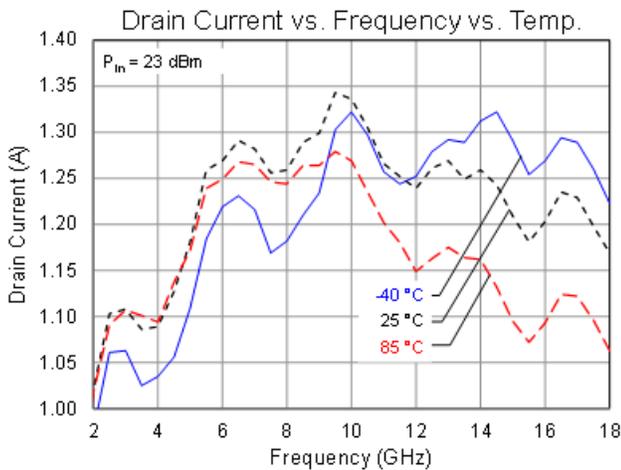
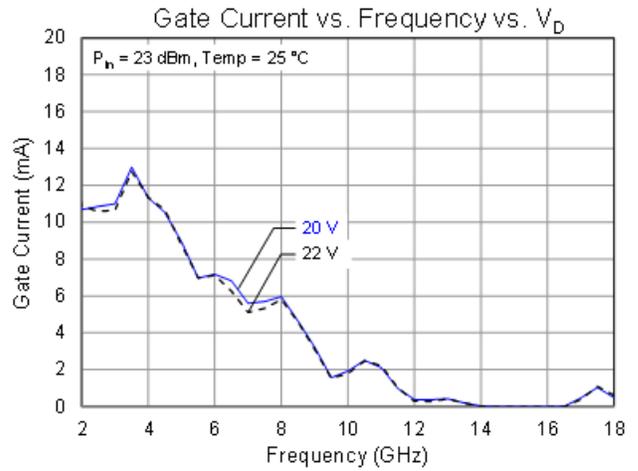
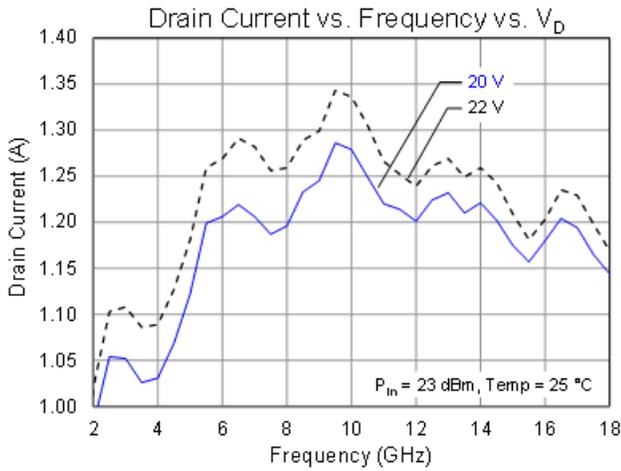
Performance Plots – Large Signal

Test conditions unless otherwise noted: 25 °C, $V_D = +22\text{ V}$, $I_{BQ} = 450\text{ mA}$, CW.



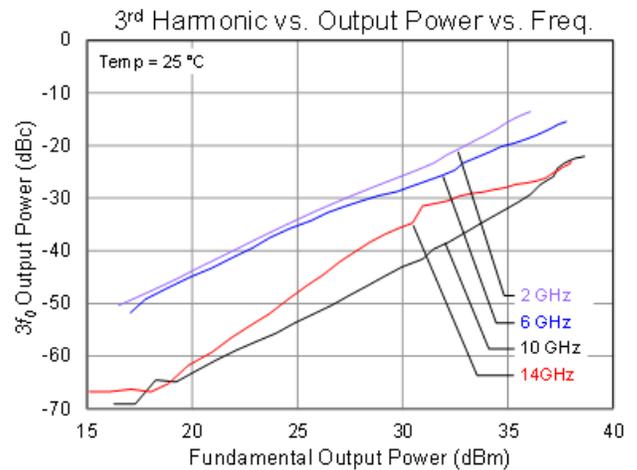
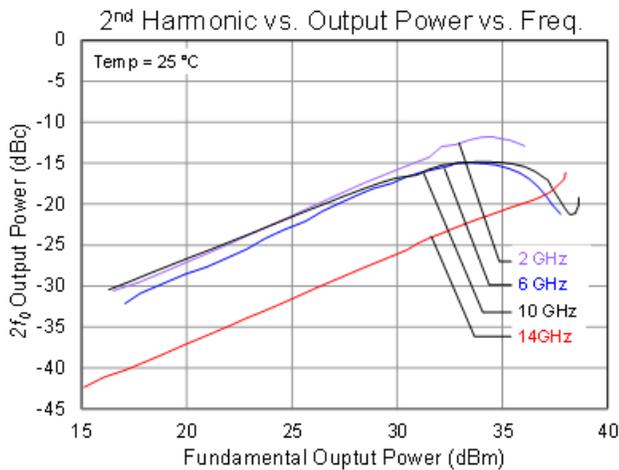
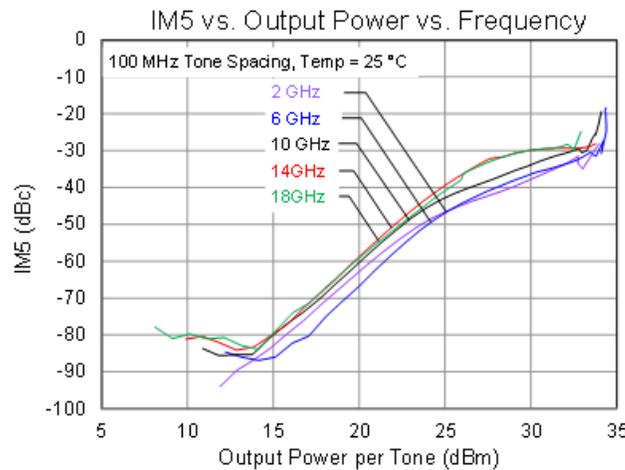
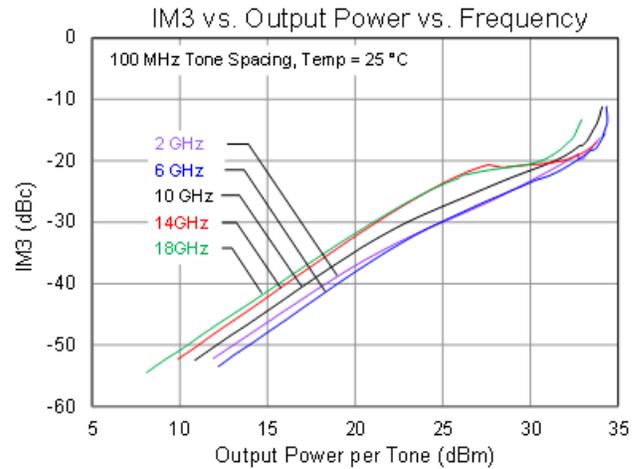
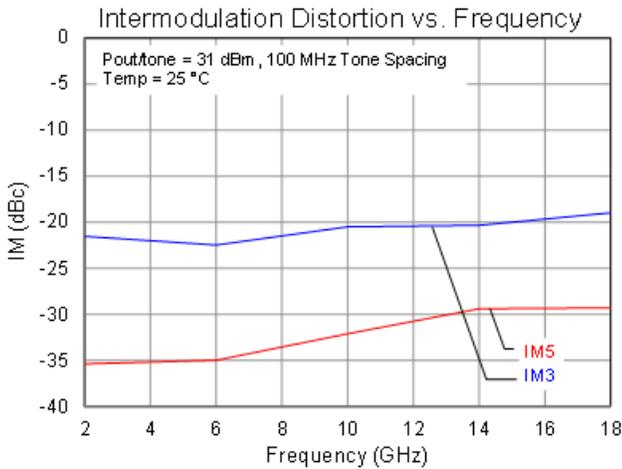
Performance Plots – Large Signal

Test conditions unless otherwise noted: 25 °C, $V_D = +22\text{ V}$, $I_{DQ} = 450\text{ mA}$, CW.



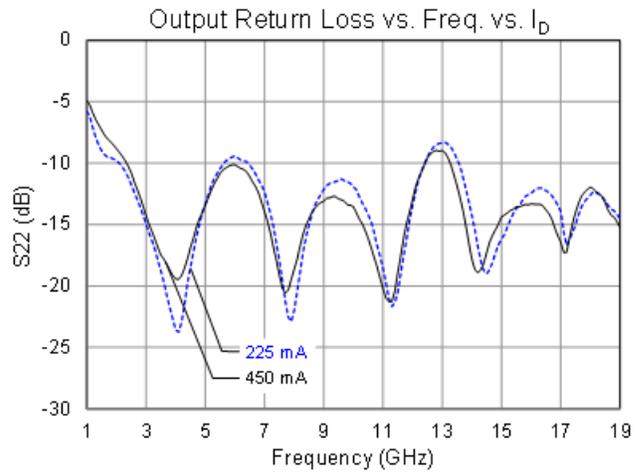
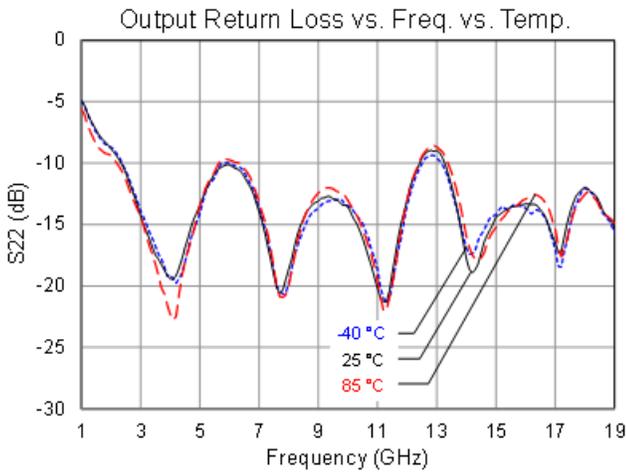
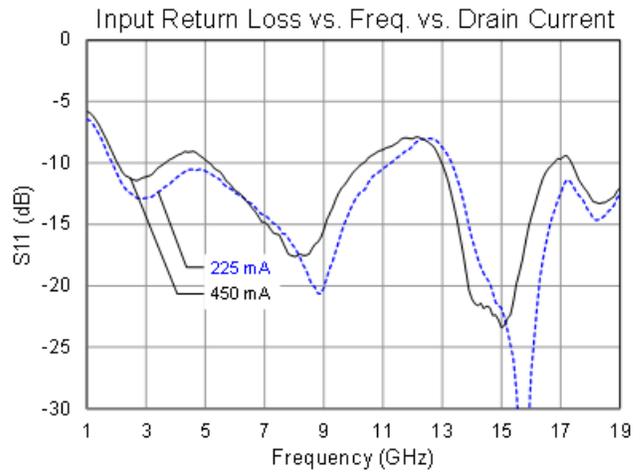
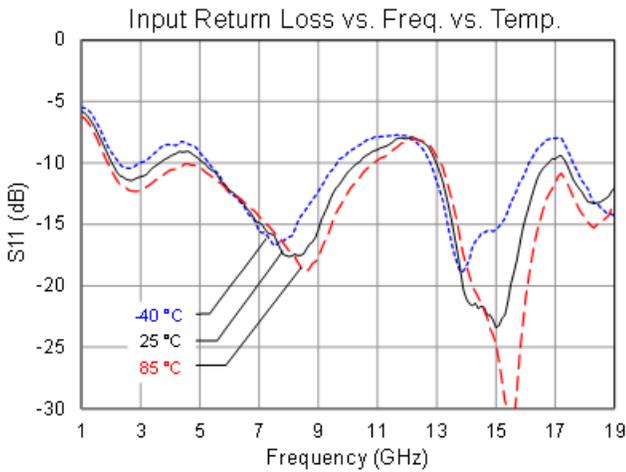
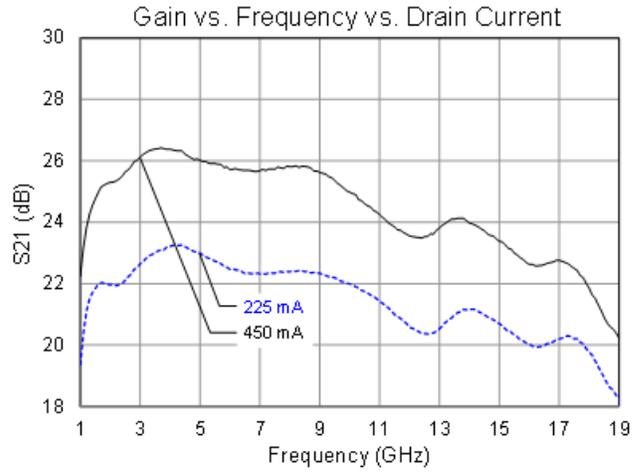
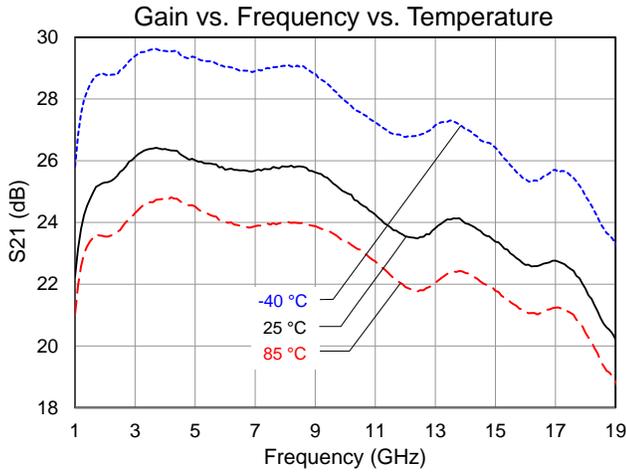
Performance Plots – Linearity

Test conditions unless otherwise noted: 25 °C, $V_D = +22\text{ V}$, $I_{BQ} = 450\text{ mA}$, CW.



Performance Plots – Small Signal

Test conditions unless otherwise noted: 25 °C, $V_D = +22\text{ V}$, $I_{DQ} = 450\text{ mA}$, CW.



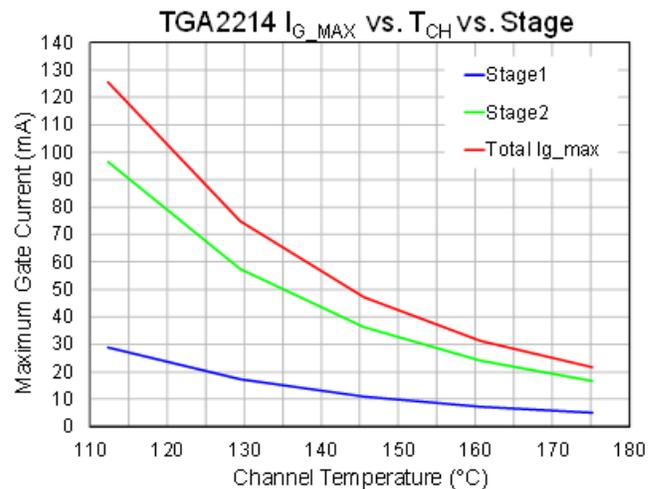
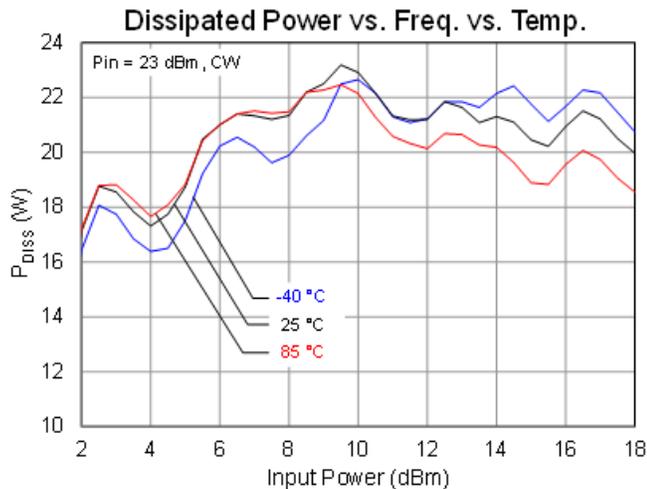
Thermal and Reliability Information

Parameter	Test Conditions	Value	Units
Thermal Resistance (θ_{JC}) ⁽¹⁾	$T_{BASE} = 85\text{ }^{\circ}\text{C}$, Freq = 9.5 GHz, $V_D = 22\text{ V}$, $P_{IN} = 23\text{ dBm}$, $I_{DQ} = 450\text{ mA}$, $I_{DRIVE} = 1.28\text{ A}$,	3.921	$^{\circ}\text{C} / \text{W}$
Channel Temperature T_{CH} (Quiescent) ^(1,2)	$P_{OUT} = 37.5\text{ dBm}$, $P_{DISS} = 22.7\text{ W}$	174	$^{\circ}\text{C}$

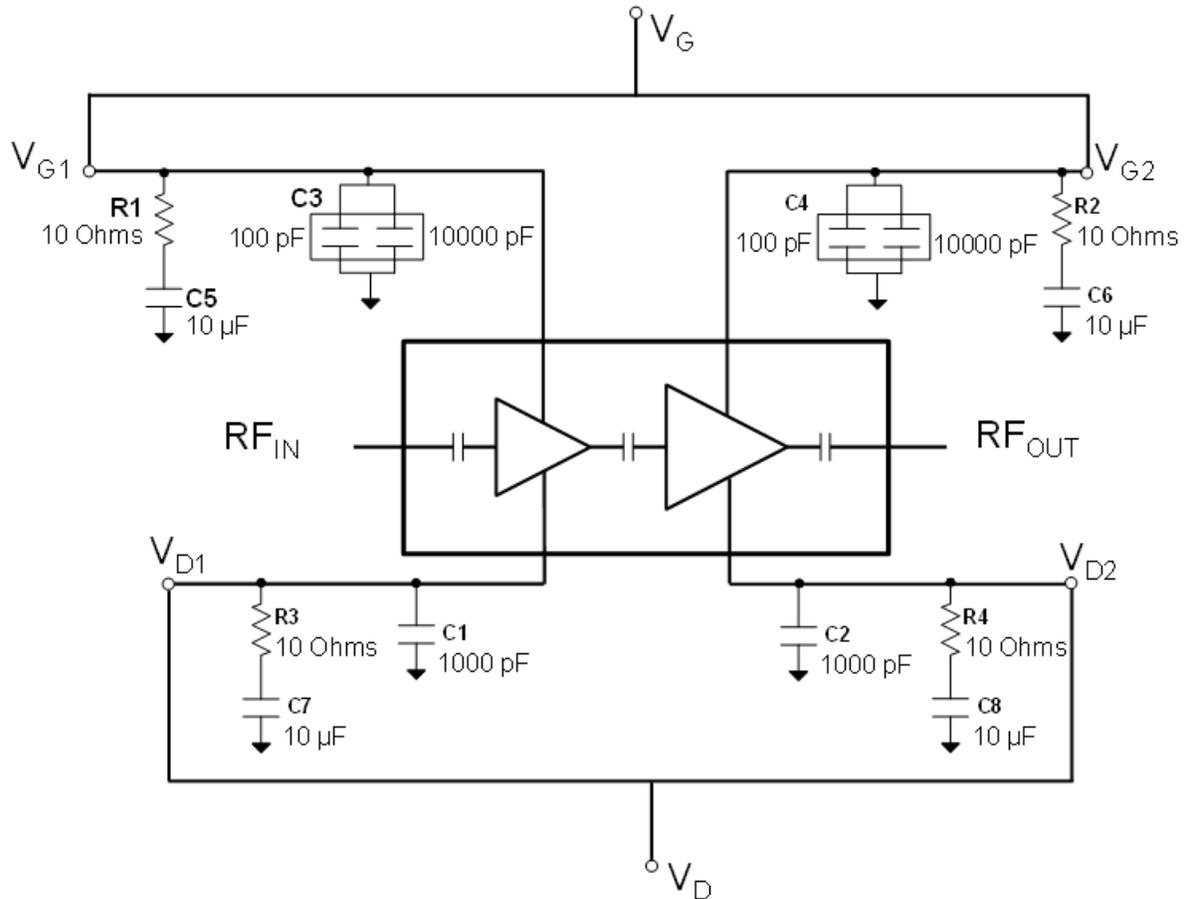
Notes:

1. Die mounted to 20 mil CuMo carrier plate with eutectic die attach. Thermal resistance determined to the back of carrier (85 $^{\circ}\text{C}$).
2. IR Scan equivalent temperature. Refer to the following document: [GaN Device Channel Temperature, Thermal Resistance, and Reliability Estimates](#)

Power Dissipation and Maximum Gate Current



Applications Information and Pad Layout



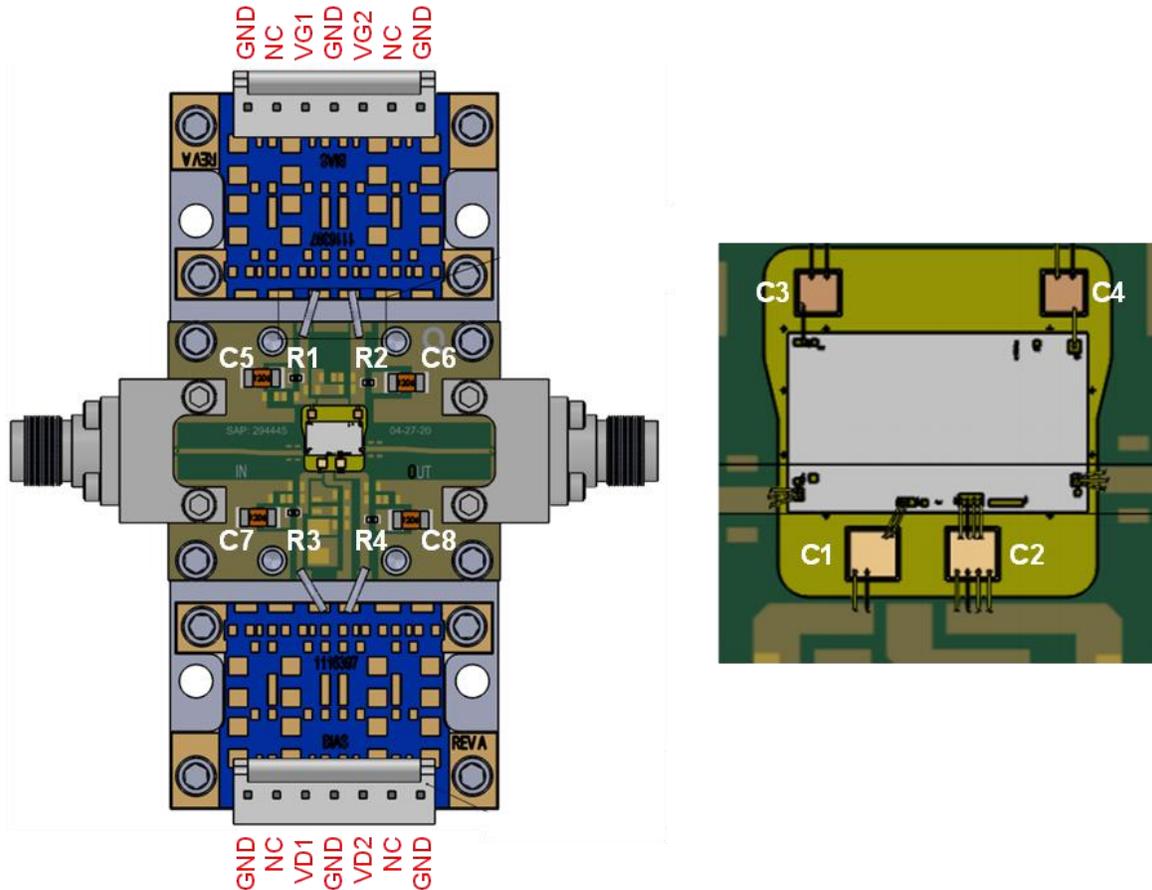
Bias-Up Procedure

1. Set I_D limit to 1.4 A, I_G limit to 20 mA
2. Apply -5 V to V_G
3. Apply +22 V to V_D ; ensure I_{DQ} is approx. 0 mA
4. Adjust V_G until $I_{DQ} = 450$ mA ($V_G \sim -2.3$ V Typ.).
5. Turn on RF supply

Bias-Down Procedure

1. Turn off RF supply
2. Reduce V_G to -5 V; ensure I_{DQ} is approx. 0 mA
3. Set V_D to 0 V
4. Turn off V_D supply
5. Turn off V_G supply

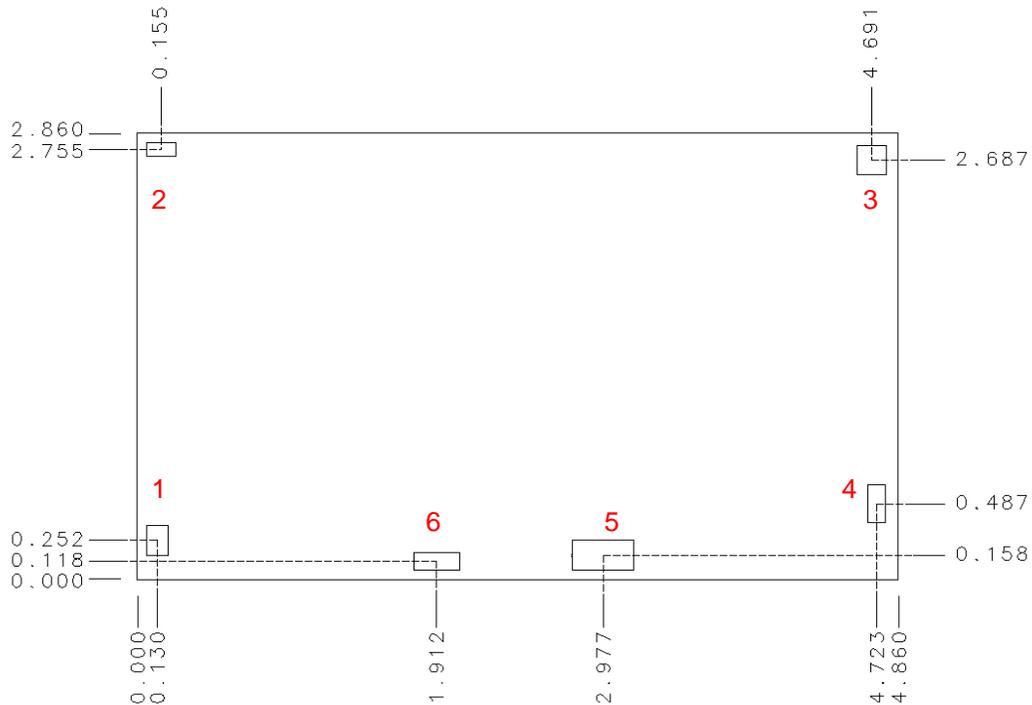
Evaluation Board (EVB) Layout Assembly



Bill of Materials

Reference Des.	Value	Description	Manuf.	Part Number
C1, C2	1000 pF	Cap, +50 V, 10 %, SLCC	Presidio	MSA3535B102K2H5C-F
C3, C4	100 pF //	Cap, +50 V, 20 %, X7R, MLCC	Presidio	MVB3030X103M2H5C1F
C5, C6, C7, C8	10 μ F	Cap, 1206, 20 %, +50 V, X5R	Various	–
R1, R2, R3, R4	10 Ohms	Res, 0402, 5 %	Various	–

Mechanical Information and Bond Pad Description



Units: millimeters
Thickness: 0.100
Die x,y size tolerance: ± 0.008
Ground is backside of die

Bond Pad Description

Pad No.	Symbol	Pad Size (mm)	Description
1	RF IN	0.150 x 0.200	RF Input; matched to 50 Ω , DC blocked
2	$V_{G1}^{(1)}$	0.200 x 0.100	Gate voltage for stage 1, bias network is required; see Application Circuit on page 9 as an example.
3	$V_{G2}^{(1)}$	0.200 x 0.200	Gate voltage for stage 2, bias network is required; see Application Circuit on page 9 as an example.
4	RF OUT	0.150 x 0.200	RF Output; matched to 50 Ω , DC blocked
5	$V_{D2}^{(2)}$	0.400 x 0.200	Drain voltage for stage 2, bias network is required; see Application Circuit on page 9 as an example
6	$V_{D1}^{(2)}$	0.300 x 0.125	Drain voltage for stage 1, bias network is required; see Application Circuit on page 9 as an example

Notes:

- 1) V_{G1} & V_{G2} may be tied together off-chip.
- 2) V_{D1} & V_{D2} may be tied together off-chip.

Assembly Notes

Component placement and die attachment assembly notes:

- Vacuum pencils and/or vacuum collets are the preferred method of pick up.
- Air bridges must be avoided during placement.
- The force impact is critical during auto placement.
- Conductive epoxy attachment may be used for small-signal low power dissipation die.
- Follow manufacture instructions for epoxy curing.

Reflow process assembly notes:

- Use AuSn (80/20) solder and limit exposure to temperatures above 300°C to 3-4 minutes, maximum.
- An alloy station or conveyor furnace with reducing atmosphere should be used.
- Do not use any kind of flux.
- Coefficient of thermal expansion matching is critical for long-term reliability.
- Devices must be stored in a dry nitrogen atmosphere.

Interconnect process assembly notes:

- Thermosonic ball bonding is the preferred interconnect technique.
- Force, time, and ultrasonic are critical parameters.
- Aluminum wire should not be used.
- Devices with small pad sizes should be bonded with 0.0007-inch wire.

Handling Precautions

Parameter	Rating	Standard
ESD – Human Body Model (HBM)	1B	ANSI/ESD/JEDEC JS-001



Caution!
ESD-Sensitive Device

RoHS Compliance

This part is compliant with 2011/65/EU RoHS directive (Restrictions on the Use of Certain Hazardous Substances in Electrical and Electronic Equipment) as amended by Directive 2015/863/EU.

This product also has the following attributes:

- Lead Free
- Halogen Free (Chlorine, Bromine)
- Antimony Free
- TBBP-A (C₁₅H₁₂Br₄O₂) Free
- SVHC Free
- PFOS Free

Contact Information

For the latest specifications, additional product information, worldwide sales and distribution locations:

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Email: customer.support@qorvo.com

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